

Notice of References Cited		Application/Control No. 10/593,353	Applicant(s)/Patent Under Reexamination DAHNE ET AL.	
		Examiner RAYMOND P. YEAGER	Art Unit 4121	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0172716	11-2002	Walt et al.	424/491
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Decher and Schlenoff, 2002. Multilayer Thin Films; Chapter 1. Polyelectrolyte Multilayers pp. 87-97; Chapter 8. Layer by Layer Assembly of Nanoparticles and Nanocolloids p; Chapter 12. Coated Colloids: preparation, Characterization, Assembly, and Utilization. pp. 331-362.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.